


<b>Search Notes</b> 	<b>Application/Control No.</b> 10575093	<b>Applicant(s)/Patent Under Reexamination</b> MURAKATA ET AL.
	<b>Examiner</b> Loewe, Sun Jae Y	<b>Art Unit</b> 1626

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
STN structure	8/27/2007	sl
palm inventor (all inventors)	8/27/2007	sl

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner